Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/693,909	UMESH ET AL.		
Examiner	Art Unit		
DANH C. LE	2683		

SEARCHED					
Class	Subclass	Date	Examiner		
F(20)					
455	562.1	7 29 05	RL		
	56	111			
	273				
370	334				
	249				
347	757				
9	•				
34.2	372				
	373				
		1	1		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Name Search (Check for buble latent)	7 29 05	DCL		
EAST Search (USP, USPUB)	7/30/05	DCL		
EAST Searh	7/31/05	DCL_		
(DERWENT, EPU, JPO)				
Lee Ngujen (455)				
Hun Vuong (455)		1		
Interference Search				